

**Search Notes**

Application/Control No.

10/051,805

Examiner

Stephen M. Brinich

Applicant(s)/Patent under  
Reexamination

NAKAMI ET AL.

Art Unit

2624

**SEARCHED**

Class	Subclass	Date	Examiner
358	1.9, 2.1, 406, 504		
382	162, 168		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR